

Citations for Ion : **Cr**

Pub. Year	Authors, Title, Journal Citation and Comments	Citation Numb
1962	Powers, D. Whaling, W. 'Range of Heavy Ions in Solids' <i>Phys. Rev.</i> , 126, 61-69 (1962) <i>Comment</i> : R. 50-500 keV N, Ne, Ar, Kr, Xe -> Be, B, C, Al	1962-Powe
1965	Jahnig, F. Kalus, J. 'Messung De Anisotropen Abbremung von Chromatomen in Energiebereich 20-90 eV in Einem Vanadiumeinkristall Mit der Kernfluoreszenzmethode' <i>Z. Naturforschg.</i> 20A, 387-90 (1965) <i>Comment</i> : S. 20-90 eV Cr -> V (Cryst.)	1965-Jahn
1965	Kalus, J. 'Abbremsung von Chrom-Atomen Mit Einer Energie von 20-90 eV in Verschiedenen Substanzen' <i>Z. Naturforschg.</i> 20A, 391-94 (1965) <i>Comment</i> : R. 20-90 eV Cr -> V, V2O5, Voc2O4, V(CH(COCH3)2)3 V(CH(COCH3)2)2	1965-Kalu
1966	VanLint, V. A. J. Wyatt, M. E. Schmitt, R. A. Suffredini, C. S. Nichols, D. K. 'Range of Photoparticle Recoil Atoms on Solids' <i>Phys. Rev.</i> , 147, 242-48 (1966) <i>Comment</i> : R. (.001- 5 epsilon) Ti, Sc, Cr, Fe, Mn, Ni, Co, Ge, Zr, Y, Sr, Mo, Rh, Pd, Ag, Cd, Sn, Gd, Ta, Au, Th -> Al, Cu	1966-VanL
1967	Erikson, L. Davies, J. A. Jespersgaard, P. 'Range Measurements in Oriented Tungsten Single Crystals (0.1-1.0 MeV). Part I: Electronic and Nuclear Stopping Powers.' <i>Phys. Rev.</i> , 161, 219-34 (1967) <i>Comment</i> : R, dR. (0.1-1.0 MeV) Na, P, K, Cr, Cu, Br, Kr, Rb, Sb, Xe, W, Rn -> W (Cryst.); (40-500 keV) Na, K, Kr, Xe -> Al (Cryst.)	1967-Erik2
1968	Bowman, W. W. Lanzafame, F. M. Cline, C. K. Yu, Yu-Wen Blann, M. 'Recoil Ranges of 0.2 - 5.2 MeV Ions in Vanadium, Nickel, Iron, Zirconium and Gold.' <i>Phys. Rev.</i> , 165, 485-93 (1968) <i>Comment</i> : R, dR. Ion(ZI=12-81, E=0.22-5.2 MeV) -> V, Ni, Zr, Au	1968-Bowm
1968	Fastrup, B. Borup, A. Hvelplund, P. 'Stopping Cross Section in Atmospheric Air of 0.2 - 0.5 MeV Atoms with 6 <= Z1 <= 24.' <i>Can. J. Phys.</i> , 46, 489-95 (1968) <i>Comment</i> : S. (100-1000 keV) C, N, O, Ne, N, Mg, P, S, Cl, Sc, Ca, Ti Al, Ar, K, Cr -> Air	1968-Fast
1968	Hvelplund, P. Fastrup, B. 'Stopping Cross Section in Carbon of 0.2 - 1.5 MeV Atoms with 21 <= Z1 <= 39.' <i>Phys. Rev.</i> , 165, 408-14 (1968) <i>Comment</i> : S. (230 - 1470 keV) Sc, Ti, Cr, Mn, Fe, Co, Cu, Ge, Br, W, Y -> C	1968-Hvel2

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1970	Fehsenfeld, F. Scharmann, A. 'Messungen der Eindringtiefen von Ionen in Lif-Zns-Und Csj-Aufdampfschichten' <i>Z. Physik, 230, 435-42 (1970)</i> <i>Comment : R. 5-60 keV H, He Ne, Ar, Kr -> LiF, ZnS, CsJ</i>	1970-Fehs
1974	Blok, H. Kiely, F. M. Pate, B. D. Hanappe, F. Pelier, J. 'Further Measurement of the Track Length of Heavy Ions in Mica' <i>Nucl. Inst. Methods, 119, 307-12 (1974)</i> <i>Comment : R. (2.7-160 MeV) Al, Ar, Ca, Cr, Ni, Se, Kr, Ag -> Mica</i>	1974-Blok
1974	Jensen, M. Larsson, L. Mathiesen, O. Rosander, R. 'Experimental and Theoretical Absorptance Profiles of Tracks of Fast Heavy Ions in Nuclear Emulsion' <i>Univ. Lund., Sweden (1974)</i> <i>Comment : R. 0.3 < Beta < 0.8 Si, P, Ca, Cr, Fe -> Emulsion</i>	1974-Jens
1976	Grant, W. A. Dodds, D. Williams, J. S. Christodoulides, C. E. Baragiola, R. A. 'Heavy Ion Ranges in Silicon and Aluminum' <i>Ion Implantation in Semiconductors, Ed. by F. Chernow, J. A. Borders, D. K. Brice, 693-703 (1976)</i> <i>Comment : R. 0.01 < Epsilon < 0.8 Cr, Ni, Ga, As, Br, Mo, Cs, La, Nd, Dy, Ta, Pt, Au, Pb -> Si, Al</i>	1976-Gran
1976	Williams, J. S. 'The Application of Low Angle Rutherford Backscattering to Surface Layer Analysis' <i>Meyer, G. Linker and F. Kappeler (Ed.): Ion Beam Surface Layer Analysis, Plenum, N. Y., P. 223-34 (1976)</i> <i>Comment : R, dR. 5 keV Cr -> Ge, 20 keV Pb -> Si</i>	1976-Will
1977	Iwaki, M. Namba, S. Yoshida, K. Soda, N. Yukawa, K. 'Concentration Profiles of Nickel and Chromium Implanted in Mild Steel' <i>Jap. J. Appl. Phys., 16, 1475-1476 (1977)</i> <i>Comment : R. 150 keV Ni, Cr -> Steel</i>	1977-Iwak
1977	Lemberg, I. K. Pasternack, A. A. 'A New Method for Studying the Nuclear and Electronic Mechanisms of Heavy Ion Stopping in Matter' <i>Nucl. Inst. Methods, 140, 71-80 (1977)</i> <i>Comment : S. 0.5-1.5 MeV Cr -> Cr, Ni -> Ni, Cd -> Cd</i>	1977-Lemb
1978	Covino, B. S. Sartwell, B. D. Needham, P. B. 'Anodic Polarization Behavior of Fe-Cr Surface Alloys Formed by Ion Implantation' <i>J. Electrochem. Soc., 125, 366-369 (1978)</i> <i>Comment : R. 25 keV Cr -> Fe</i>	1978-Covi
1978	Sartwell, B. D. 'Formation of Corrosion-Resistant Surface Alloys by Metal Implantation' <i>Thin Solid Films, 54, 233-242 (1978)</i> <i>Comment : R, dR. 25 keV Cr, Ni -> Fe</i>	1978-Sart

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1979	Okabe, Y. Iwaki, M. Takahashi, K. Hayashi, H. Namba, S. 'Electrochemical Properties of Ion Implanted Steel' <i>Preprint (1979) 5</i> <i>Comment : R, Dleta R. 150 keV Cr -> Steel</i>	1979-Okab
1979	Santry, D. C. Werner, R. D. Westcott, O. M. 'The Range of 120 keV Ions in Solids' <i>IEEE Trans. Nucl. Sci., Ns-26, 1331-1334 (1979)</i> <i>Comment : R, dR. 120 keV Mg, Al, P, S, Cl, K, Ar, Cr, Mn, Cu, Zn, Ga, As, Br, Kr, Rb, Ag, In, Sn, Sb, Te, I, Xe, Cs, Ba, Pr, Au, Hg, Tl, Pb, Bi -> Be, C, Al, Si</i>	1979-Sant
1979	Switkowski, Z. E. Petty, R. J. Heggie, J. C. P. Clark, G. J. 'Application of the Resonant 52Cr(p,gamma)53Mn Reaction to the Measurement of Chromium Depth Distributions' <i>Preprint (1979) 7</i> <i>Comment : R, dR. 10 keV Cr -> Solar Absorber Surface</i>	1979-Swit
1980	Campbell, A. B. Sartwell, B. D. Needham, P. B. Jr. 'Depth Profiling of Ion-Implanted Alloys' <i>J. Appl. Phys., 50, 283-289 (1980)</i> <i>Comment : R, dR. 25 keV Ni, Cr, Al -> Fe</i>	1980-Camp
1980	Wilson, R. G. Vasudev, P. K. Jamba, D. M. Evans, C. A. 'Chromium Concentrations, Depth Distributions, and Diffusion Coefficient in Bulk and Epitaxial GaAs and in Si' <i>Appl. Phys. Letters, 36, 215-218 (1980)</i> <i>Comment : R, dR. 200 keV Cr -> Si</i>	1980-Wils2
1983	Mannspenger, H. Kalbitzer, S. Demond, F. J. Damjantschitsch, H. 'Projection Factors of Low Energy Ion Ranges' <i>Nucl. Inst. Methods, 209/210, 49-55 (1983)</i> <i>Comment : R, H, C, Na, Al, Si, Ar, Cr (.04<epsilon<1) -> Si, Ge</i>	1983-Mann
1986	Lennard, W. N. Geissel, H. Jackson, D. P. Phillips, D. 'Electronic Stopping Values for Low Velocity Ions (9 <= Z1 <= 92) in Carbon Targets' <i>Nucl. Inst. Methods, B13, 127 (1986)</i> <i>Comment : S. (16 keV/amu) F, Ne, Na, Mg, Al, P, Cl, Ar, K, Sc, Cr, Mn, Cu, Kr, Nb, Ag, In, Xe, Sm, Yb, Au, Bi, U -> C</i>	1986-Lenn2
1996	Hari, K. V. Pathak, A. P. Sharma, S. K. Shyam, K. Nath, N. 'Energy Loss of MeV Heavy Ions in Carbon' <i>Nucl. Inst. Methods, B108, 223-226 (1996)</i> <i>Comment : S. Z1 (O - Cu) at 0.1-1.0 MeV/amu -> C</i>	1996-Hari
1996	Kumar, S. Sharma, S. K. Nath, N. Harikumar, V. Pathak, A. P. 'Stopping Power of Carbon for Heavy Ions up to Copper' <i>Rad. Effects, 139, 197-206 (1996)</i> <i>Comment : S. Sc, Ti, Cr, Mn, Fe, Cu (0.2-1.0 MeV/amu -> C</i>	1996-Kuma

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2000	Sharma, A. Kumar, S. Sharma, S. K. Diwan, P. K. Nath, N. 'Stopping Power of Mylar for Heavy Ions up to Copper' <i>Nucl. Inst. Methods, B170, 323-328 (2000)</i> <i>Comment : S. Na,Al,Cl,Sc,Ti,V,Cr,Mn,Ni,Cu (0.3 - 2.3 MeV/u) -> Mylar</i>	2000-Shar
2001	Zhang, Y. Possnert, G. Whitlow, H. J. 'Measurements of the Mean Energy-Loss of Swift Heavy Ions in Carbon with High Precision' <i>Nucl. Inst. Methods, B183, 34-37 (2001)</i> <i>Comment : S. Li,Be, B, C, N, O, F,Na,Mg,Al,Si,Cr,Mn,Fe (100 - 800 keV/u) -> C</i>	2001-Zhan
2002	Zhang, Y. 'High-Precision Measurement of Electronic Stopping Powers for Heavy Ions using High-Resolution Time-of-Flight Spectrometry' <i>Nucl. Inst. Methods, B196, 1-15 (2002)</i> <i>Comment : S. Stopping of 18 Heavy Ions into C, Al and Au Targets</i>	2002-Zhan
2003	Zhang, Yanwen Weber, W. J. 'Validity of Bragg's rule for heavy-ion stopping in silicon carbide' <i>Phys. Rev. B68, 235317 (2003)</i> <i>Comment : S. O - Cu (0.05 - 0.4 MeV/n) -> SiC</i>	2003-Zha1
2004	Zhang, Y. Weber, W. Whitlow, H. J. 'Electronic Stopping Powers for Heavy Ions in Silicon' <i>Nucl. Inst. Methods, B215, 48-56 (2004)</i> <i>Comment : S. 14 light ions (Be-Cu) -> Si</i>	2004-Zha3